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SJ

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SJ/T 11491-2015

**Test methods for measurement of interstitial oxygen content in
silicon by short baseline infrared absorption spectrometry**

短基线红外吸收光谱法测量硅中间隙氧含量

(English Translation)

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What this standard covers

This Standard specifies the baseline Infrared Spectroscopy silicon interstitial oxygen content was short. This Standard applies at room temperature with a short baseline infrared absorption method, measuring the low-resistivity silicon single crystal n-type and p-type silicon single crystal interstitial oxygen content. Effective range to measure the oxygen content of from $1 \times 10^{16} \text{at.cm}^{-3}$ to test interstitial oxygen in silicon single maximum solid solubility.

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